Composite Devices Silicon N-Channel MOS/Diode Epitaxial Planar

# SSM5H90ATU

### 1. Applications

· High-Speed Switching

#### 2. Features

(1) Combined an N-channel MOSFET and a diode in one package.

### 2.1. MOSFET Features

(1) Low drain-source on-resistance

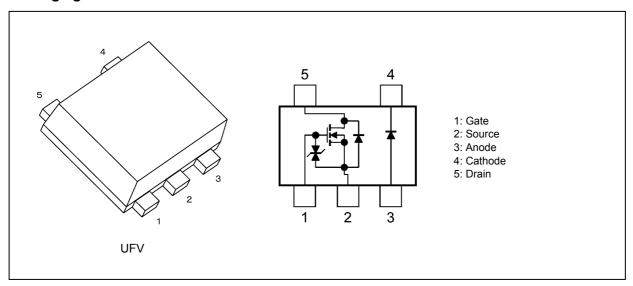
:  $R_{DS(ON)} = 65 \text{ m}\Omega \text{ (max) (@V_{GS} = 4.0 V)}$  $R_{DS(ON)} = 89 \text{ m}\Omega \text{ (max) (@V_{GS} = 2.5 V)}$ 

(2) 2.5-V gate drive voltage.

### 2.2. Diode Features

(1) Low reverse current:  $I_R$  = 0.1  $\mu A$  (typ.) (@ $V_R$  = 30 V)

### 3. Packaging and Internal Circuit



### 4. Absolute Maximum Ratings (Note)

# 4.1. Absolute Maximum Ratings of the MOSFET (Unless otherwise specified, $T_a$ = 25 °C)

Characteristics		Symbol	Rating	Unit
Drain-source voltage		$V_{DSS}$	20	V
Gate-source voltage		$V_{GSS}$	±10	
Drain current	(Note 1)	I <sub>D</sub>	2.4	Α
Drain current (pulsed)	(Note 1)	I <sub>DP</sub>	4.8	
Channel temperature		T <sub>ch</sub>	150	°C

Note 1: Ensure that the channel temperature does not exceed 150 °C.



## 4.2. Absolute Maximum Ratings of the Diode (Unless otherwise specified, Ta = 25 °C)

Characteristics	Symbol	Rating	Unit
Peak reverse voltage	$V_{RM}$	85	V
Reverse voltage	V <sub>R</sub>	80	
Peak forward current	I <sub>FM</sub>	200	mA
Average rectified current	I <sub>O</sub>	100	
Non-repetitive peak forward surge current (t = 10 ms)	I <sub>FSM</sub>	1	Α
Junction temperature	T <sub>j</sub>	125	°C

# 4.3. Absolute Maximum Ratings of the Common Section (Unless otherwise specified, T<sub>a</sub> = 25 °C)

Characteristics			Symbol	Rating	Unit
Power dissipation		(Note 1)	$P_{D}$	0.5	W
Power dissipation	(t = 10 s)	(Note 1)		0.8	
Storage temperature		,	T <sub>stg</sub>	-55 to 125	°C

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 1: PD for the entire IC

Device mounted on a 25.4 mm × 25.4 mm × 1.6 mm FR-4 glass epoxy board (Cu pad: 645 mm<sup>2</sup>)

Note: The MOSFETs in this device are sensitive to electrostatic discharge. When handling this device, the worktables, operators, soldering irons and other objects should be protected against anti-static discharge.

Note: The channel-to-ambient thermal resistance,  $R_{th(ch-a)}$ , and the drain power dissipation,  $P_D$ , vary according to the board material, board area, board thickness and pad area. When using this device, be sure to take heat dissipation fully into account.

### 5. Electrical Characteristics

## 5.1. Static Characteristics of the MOSFET (Unless otherwise specified, Ta = 25 °C)

Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage current		I <sub>GSS</sub>	$V_{GS} = \pm 10 \text{ V}, V_{DS} = 0 \text{ V}$	_	_	±10	μΑ
Drain cut-off current		I <sub>DSS</sub>	V <sub>DS</sub> = 20 V, V <sub>GS</sub> = 0 V			10	
Drain-source breakdown voltage		V <sub>(BR)DSS</sub>	$I_D = 1 \text{ mA}, V_{GS} = 0 \text{ V}$	20			V
Drain-source breakdown voltage	(Note 1)	V <sub>(BR)DSX</sub>	$I_D = 1 \text{ mA}, V_{GS} = -10 \text{ V}$	12	_	_	
Gate threshold voltage	(Note 2)	$V_{th}$	$V_{DS} = 3 \text{ V}, I_{D} = 1 \text{ mA}$	0.5		1.2	
Drain-source on-resistance	(Note 3)	R <sub>DS(ON)</sub>	I <sub>D</sub> = 1.5 A, V <sub>GS</sub> = 4.0 V	_	53	65	mΩ
			I <sub>D</sub> = 1.5 A, V <sub>GS</sub> = 2.5 V	_	64	89	
Forward transfer admittance	(Note 3)	Y <sub>fs</sub>	V <sub>DS</sub> = 3 V, I <sub>D</sub> = 1.0 A	3	6	_	S

Note 1: If a reverse bias is applied between gate and source, this device enters  $V_{(BR)DSX}$  mode. Note that the drain-source breakdown voltage is lowered in this mode.

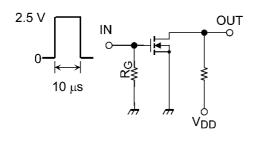
Note 2: Let  $V_{th}$  be the voltage applied between gate and source that causes the drain current ( $I_D$ ) to below (1 mA for this device). Then, for normal switching operation,  $V_{GS(ON)}$  must be higher than  $V_{th}$ , and  $V_{GS(OFF)}$  must be lower than  $V_{th}$ . This relationship can be expressed as:  $V_{GS(OFF)} < V_{th} < V_{GS(ON)}$ .

Take this into consideration when using the device.

Note 3: Pulse measurement.

# 5.2. Dynamic Characteristics of the MOSFET (Unless otherwise specified, $T_a$ = 25 °C)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Input capacitance	C <sub>iss</sub>	V <sub>DS</sub> = 10 V, V <sub>GS</sub> = 0 V, f = 1 MHz	_	200	_	pF
Reverse transfer capacitance	C <sub>rss</sub>		_	13	_	
Output capacitance	Coss		_	40	_	
Switching time (turn-on time)	t <sub>on</sub>	$V_{DD} = 10 \text{ V}, I_D = 2 \text{ A},$	_	9	_	ns
Switching time (turn-off time)	t <sub>off</sub>	$V_{GS}$ = 0 V to 2.5 V, $R_{G}$ = 4.7 $\Omega$ , See Figure 5.2.1, 5.2.2.	_	9.5	_	



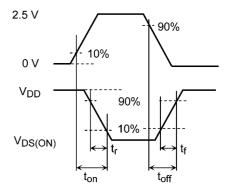


Fig. 5.2.1 Test Circuit of Switching Time

Fig. 5.2.2 Input Waveform/Output Waveform

# 5.3. Gate Charge Characteristics of the MOSFET (Unless otherwise specified, T<sub>a</sub> = 25 °C)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Total gate charge (gate-source plus gate-drain)	$Q_g$	V <sub>DD</sub> = 10 V, I <sub>D</sub> = 2.4 A	_	2.2	_	nC
Gate-source charge	$Q_{gs}$	$V_{GS} = 4 V$	_	1.3	_	
Gate-drain charge	$Q_{gd}$		_	0.9	_	



# 5.4. Source-Drain Characteristics of the MOSFET (Unless otherwise specified, T<sub>a</sub> = 25 °C)

Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Diode forward voltage (	(Note 1)	$V_{DSF}$	I <sub>D</sub> = -2.4 A, V <sub>GS</sub> = 0 V	_	-0.81	-1.2	V

Note 1: Pulse measurement.

### 5.5. Characteristics of the Diode (Unless otherwise specified, T<sub>a</sub> = 25 °C)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Forward voltage	V <sub>F(1)</sub>	I <sub>F</sub> = 1 mA	_	0.62	_	V
	V <sub>F(2)</sub>	I <sub>F</sub> = 10 mA	_	0.75	_	
	V <sub>F(3)</sub>	I <sub>F</sub> = 100 mA	_	0.98	1.20	
Reverse current	I <sub>R</sub>	V <sub>R</sub> = 30 V	_	_	0.1	μΑ
		V <sub>R</sub> = 80 V	_	_	0.5	
Total capacitance	Ct	V <sub>R</sub> = 0 V, f = 1 MHz	_	0.5	3.0	pF
Reverse recovery time	t <sub>rr</sub>	I <sub>F</sub> = 10 mA, See Figure 5.5.1.	ı	1.6	4.0	ns

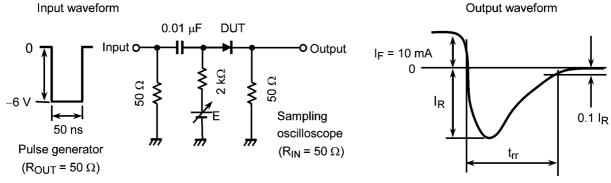
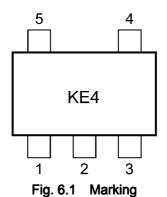


Fig. 5.5.1 Input Waveform/Output Waveform

### 6. Marking



## 7. Characteristics Curves (Note)

### 7.1. Characteristics Curves of the MOSFET

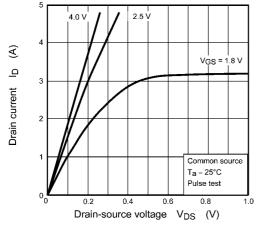


Fig. 7.1.1 I<sub>D</sub> - V<sub>DS</sub>

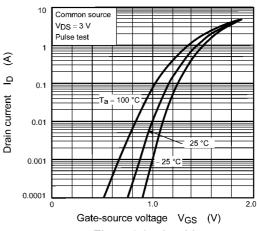


Fig. 7.1.2 I<sub>D</sub> - V<sub>GS</sub>

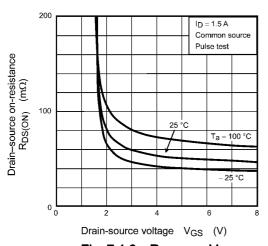


Fig. 7.1.3 R<sub>DS(ON)</sub> - V<sub>GS</sub>

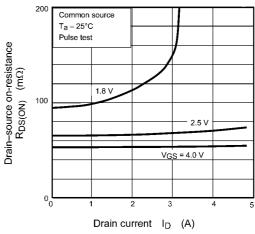


Fig. 7.1.4 R<sub>DS(ON)</sub> - I<sub>D</sub>

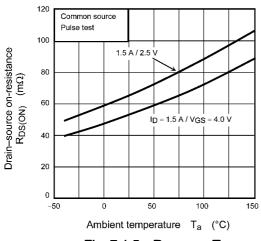


Fig. 7.1.5 R<sub>DS(ON)</sub> - T<sub>a</sub>

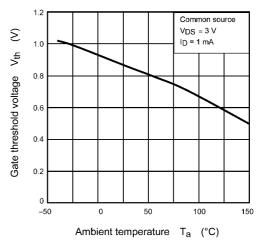
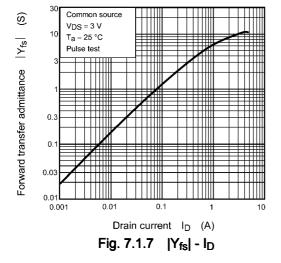


Fig. 7.1.6 V<sub>th</sub> - T<sub>a</sub>



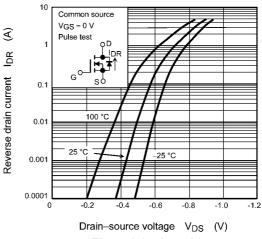
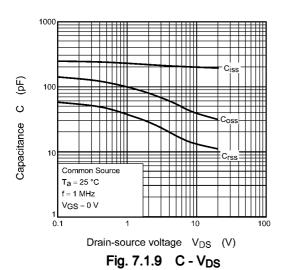


Fig. 7.1.8 I<sub>DR</sub> - V<sub>DS</sub>



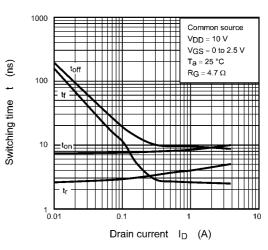
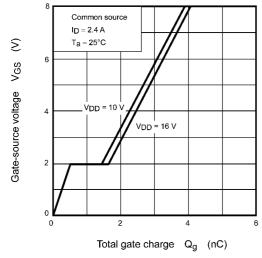


Fig. 7.1.10 t - I<sub>D</sub>



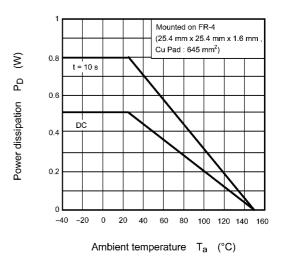


Fig. 7.1.12 PD - Ta

Fig. 7.1.11 Dynamic Input Characteristics



### 7.2. Characteristics Curves of the Diode

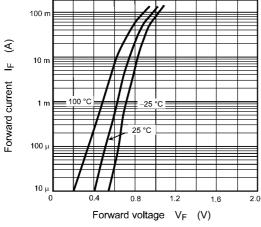


Fig. 7.2.1 I<sub>F</sub> - V<sub>F</sub>

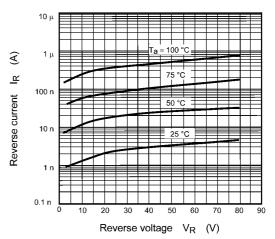


Fig. 7.2.2 I<sub>R</sub> - V<sub>R</sub>

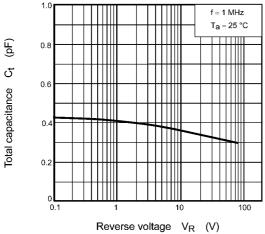


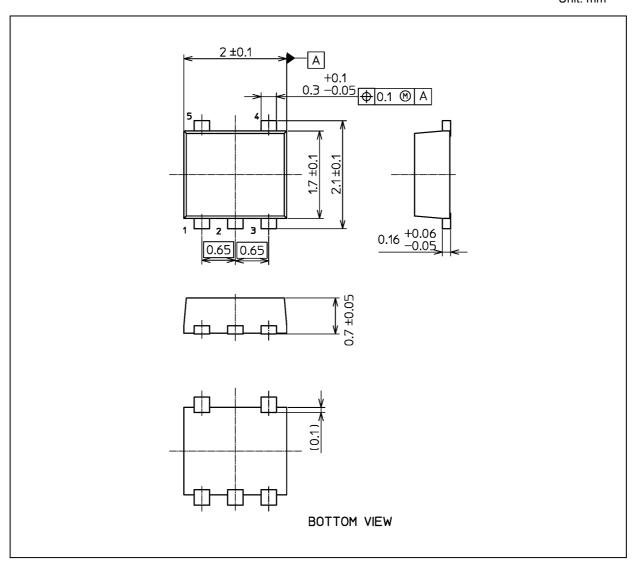
Fig. 7.2.3 C<sub>t</sub> - V<sub>R</sub>

Note: The above characteristics curves are presented for reference only and not guaranteed by production test, unless otherwise noted.



## **Package Dimensions**

Unit: mm



Weight: 7.0 mg (typ.)

	Package Name(s)	
Nickname: UFV		



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